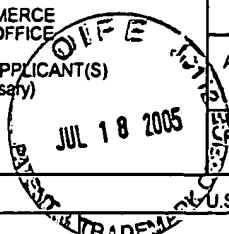
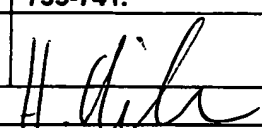



FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.017136.		APPLICATION NO. 10/656,242	
				APPLICANT NOBUHIRO YASAI, ET AL.		FILING DATE September 8, 2003	
				GROUP 1773			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
HLL	US 2004/0033339 A1	02/19/04	Fukutani et al.	428	137		
HLL	US 2004/0043208 A1	03/04/04	Fukutani et al.	428	304.4		
HLL	US 2005/0053773 A1	03/10/05	Fukutani et al.	428	209		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
HLL	JP 09-0157062 A	06/17/97	Japan			English Translation &	
HLL	JP 2001-261376	09/26/01	Japan			English Translation &	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
HLL	C.D. Adams, et al. "Monte Carlo Simulation of Phase Separation During Thin-Film Codeposition," J. Appl. Phys. 74 (3), 1 August 1993, American Institute of Physics, pp. 1707-1715.						
HLL	C.D. Adams, et al. "Transition from Lateral to Transverse Phase Separation During Film Co-deposition," Appl. Phys. Lett. 59 (20), 11 November 1991, American Institute of Physics, pp. 2535-2537.						
HLL	C.D. Adams, et al. "Phase Separation During Co-deposition of Al-Ge Thin Films," J. Mater. Res., Vol. 7, No. 3, March 1992, Materials Research Society, pp. 653-667.						
HLL	M. Atzmon, et al. "Phase Separation During Film Growth," J. Appl. Phys. 42 (2), 15 July 1992, American Institute of Physics, pp. 442-446.						
HLL	M. Jacobs, et al. "Unbalanced Magnetron Sputtered Si-Al Coatings: Plasma Conditions and Film Properties Versus Sample Bias Voltage," Surface and Coatings Technology 116-119 (1999) pp. 735-741.						
<div style="display: flex; justify-content: space-between;"> <div style="width: 40%;"> EXAMINER  </div> <div style="width: 40%;"> DATE CONSIDERED 9/26/05 </div> </div>							

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		APPLICANT NOBUHIRO YASAI, ET AL.	
		FILING DATE September 8, 2003	GROUP 1773

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
H	6,027,796	2/2000	Kondoh et al.	428	312.8		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	

EXAMINER H	DATE CONSIDERED 9/20/05
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